


<b>Search Notes</b>  	<b>Application/Control No.</b>  10822064	<b>Applicant(s)/Patent Under Reexamination</b>  MEYER ET AL.
	<b>Examiner</b>  /Chang, Rick K	<b>Art Unit</b>  3726

SEARCHED			
Class	Subclass	Date	Examiner
29	832,834	11/25/07	rc
257	737,738,778,723		
438	108,115,118,666		

SEARCH NOTES			
Search Notes		Date	Examiner
east search		11/25/07	rc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner